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John Colter, Netscape Navigator

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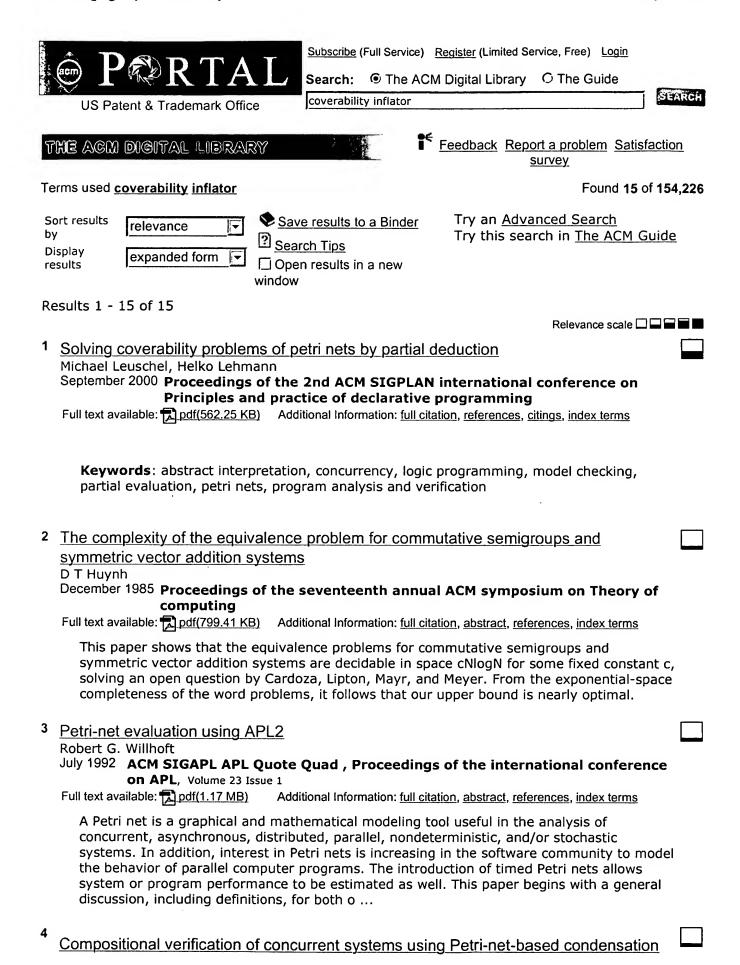
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Best 200 shown Combining GAs and Symbolic Methods for High Quality Tests of Sequential Circuits

Martin Keim, Nicole Drechsler, Rolf Drechsler, Bernd Becker February 2001 Journal of Electronic Testing: Theory and Applications, Volume 17 Issue 1

Full text available: Publisher Site

Additional Information: full citation, abstract, index terms, review

A symbolic fault simulator is integrated in a Genetic Algorithm (GA) environment to perform Automatic Test Pattern Generation (ATPG) for synchronous sequential circuits. In a two phase algorithm test length and fault coverage as well are optimized. Furthermore, not only the Single Observation Time Test Strategy is supported, but also test patterns with respect to the Multiple Observation Time Test Strategy are generated. However, there are circuits that are hard to test using random pattern s ...

Keywords: genetic algorithm, multiple observation time test strategy, sequential circuit ATPG, single observation time test strategy, symbolic simulation

2 Coverage estimation for symbolic model checking

Yatin Hoskote, Timothy Kam, Pei-Hsin Ho, Xudong Zhao

June 1999 Proceedings of the 36th ACM/IEEE conference on Design automation

Full text available: pdf(79.32 KB)

Additional Information: full citation, references, citings, index terms

SIVA: A System for Coverage-Directed State Space Search

Malay Ganai, Praveen Yalagandula, Adnan Aziz, Andreas Kuehlmann, Vigyan Singhal February 2001 Journal of Electronic Testing: Theory and Applications, Volume 17 Issue 1

Full text available: Publisher Site

Additional Information: full citation, abstract, index terms

We introduce SImulation Verification with Augmentation (SIVA), a tool for coveragedirected state space search on digital hardware designs. SIVA tightly integrates simulation with symbolic techniques for efficient state space search. Specifically, the core algorithm uses a combination of ATPG and BDDs to generate "directed" input vectors, i.e., inputs which cover behavior not excited by simulation. We also present approaches to automatically generate "li ...

Keywords: coverage, formal methods, functional verification, guided search